Verification of Compliance

Product Name

: Fanless embedded controller

Model Number

: xxxxxAEC-6613-xxxxxxxx (Where x is 0-9 , A-Z , -or blank)

for marketing purpose

Applicant

: AAEON Technology Inc.

Address

5F,NO.135,Lane 235,Pao Chiao Rd. Hsin-Tien Dist,New Taipei

City, Taiwan, R.O.C.

Report Number

: F-U070-1112-255

Issue Date

: January 5, 2012

Applicable Standards: FCC Part 15, Subpart B Class A ITE

ANSI C63.4:2003

Industry Canada ICES-003 Issue 4 CSA-IEC CISPR22: 02 Class A ITE

One sample of the designated product has been tested in our laboratory and found to be in compliance with the FCC rules cited above.





NVLAP LAB CODE 200575-0

TAF 0905 FCC CAB Code TW1053 IC Code 4699A

VCCI Accep., No. R-1527, C-1609, T-1441, G-10



Central Research Technology Co.

EMC Test Laboratory 11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.

Tel: 886-2-25984568 Fax: 886-2-25984546

(Tsun-Yu Shih/General Manager) Date: January 5, 2012

FCC Test Report

for

Fanless embedded controller

Model No. : xxxxxAEC-6613-xxxxxxxx

(Where x is 0-9, A-Z, -or blank)

for marketing purpose

Report Number : F-U070-1112-255

Date of Receipt : December 27, 2011

Date of Report : January 3, 2012

Prepared for

AAEON Technology Inc.

5F, NO.135, Lane 235, Pao Chiao Rd. Hsin-Tien Dist, New Taipei City, Taiwan, R.O.C.

Prepared by



Central Research Technology Co. EMC Test Laboratory

11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.



NVLAP LAB CODE 200575-0

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CENTRAL RESEARCH TECHNOLOGY CO.

11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.

Verification of Compliance

Equipment Under Test: Fanless embedded controller

Model No. : xxxxxAEC-6613-xxxxxxxx (Where x is 0-9, A-Z, -or blank)

for marketing purpose

Applicant: AAEON Technology Inc.

Address : 5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien Dist, New

Taipei City, Taiwan, R.O.C.

Applicable Standards : FCC Part 15, Subpart B Class A ITE

ANSI C63.4:2003

Industry Canada ICES-003 Issue 4 CSA-IEC CISPR22: 02 Class A ITE

Date of Testing : December 27~30, 2011

Deviation : N/A

Condition of Test Sample : Engineering Sample

We, **Central Research Technology Co**., hereby certify that one sample of the designated product was tested in our facility during the period mentioned above. The test records, data evaluation and Equipment Under Test (EUT) configurations shown in the present report are true and accurate representation of the measurements of the sample's EMC characteristics under the conditions herein specified.

The test results show that the EUT as described in the present report is in compliance with the requirements set forth in the standards mentioned above and apply to the tested sample identified in the present report only. The test report shall not be reproduced, except in its entirety, without the written approval of Central Research Technology Co.

PREPARED BY: Jania Chon, DATE: Jan. 5, 2012

(Janice Chou/System Executive)

(Tsun-Yu Shih/General Manager)

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1. General Description

1.1 General Description of EUT

Equipment Under Test : Fanless embedded controller

Model No. : xxxxxAEC-6613-xxxxxxxx (Where x is 0-9, A-Z, -

or blank) for marketing purpose

Power In : Supplied by the power adapter

Power Adapter Specification : Trade Name : FSP

Model No. : FSP060-DBAB1

Input : 100-240V~1.3A, 50/60Hz

Output : 12Vdc, 3.33A MAX

Highest Operating Frequency : 2.13GHz from the test specification

Manufacturer : AAEON Technology Inc.

Function Description :

The EUT is an engineering sample of the Fanless embedded controller. Please refer to the user's manual for the details.

The Model Number TF-AEC-6613-A1M-1010 was selected by its manufacturer to perform all tests. It was taken as the representative condition for test and its data are recorded in the present document.

The I/O ports of EUT are listed below:

No.	I/O Port Type	Quantity
1	D-Sub port	1
2	USB port	4
3	RS232 port	4
4	LAN port	2
5	Line output port	1
6	CF Card Slot	1

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The devices (supplied by the manufacturer) can be installed inside the EUT are listed below:

Components	Specification
M/B	GENE-CV05-xxxxxx
IVI/D	(Where x is 0-9 , A-Z , -or blank) for marketing purpose
CPU Board	GENE-CV05 REV.A0.2
CPU	INTEL ATOM D2700 2.13GHz
DC Power Board	PER-P21D REV A0.1
Memory	DSL DDR3-800 2GB
HDD	WD,WD3200BEVT,320GB
OSC	14.31818MHZ;25MHZ;32.768KHz;27MHZ
	AC Adapter Manufacturer : FSP
D 0	AC Adapter Module Number:FSP060-DBAB1
Power Supply	AC Adapter Power Rating:I/P:100~240VAC, 1.3A,
	O/P:12Vdc/5A,60Watt

1.2 Test Mode

Normal operating as the customer's requirement.

The EUT with D-Sub 1920 x 1200@60Hz resolution to monitor was selected by the manufacturer to be tested herein.

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1.3 Applied standards

According to the specifications of the manufacturer and the requirements set in 47CFR Part 15, the applied standards to evaluate the compliance of the EUT are as following, and the measurement procedures specified in ANSI C63.4: 2003 are performed.

According to 47CFR Part 15 Section 15.33(b), the test frequency range of radiated emission measurements are listed below and the EUT herein shall be tested as:

Type of EUT	Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measurement range (MHz)
	Below 1.705	30
	1.705 - 108	1000
	108 - 500	2000
	500 - 1000	5000
		5 th harmonic of the highest
	Above 1000	frequency or 40GHz,
		whichever is lower

All the test items are as following:

Applied Standards	Test Items	Results
FCC Part 15, Subpart B	☑ Conducted Emission Measurement	<u>PASS</u>
Class A ITE	☑ Radiated Emission Measurement	<u>PASS</u>

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1.4 Test Setup for the EUT

The EUT is an unique unit connected with other necessary accessories and support units listed in the next section. It has been tested against each standard after the following setup steps:

- a. Connect the EUT and all the support units to the appropriate power source.
- b. Turn on the EUT and all the accessories and support units.
- c. Install an EMC test software into the EUT and execute it under the Windows environment.
- d. The EUT sends "H" patterns to the monitor, which fills the whole screen of it.
- e. The EUT sends messages to the modems.
- f. The EUT reads/writes messages from/to the USB Flash Disk(s)/ CF Card.
- g. The EUT send 1kHz audio signal to the earphones.
- h. Another PC sends/ receives messages to/ from the EUT through a Hub by executing the command of "PING".
- i. Repeat and keep setup steps listed above before and during all tests.

EUT I/O ports / Peripherals	Exerciser Program (software)	Version of Program
EUT		
Monitor		
USB Flash Disk(s)	BurnIn Test.exe	V 6.0
Modem	Bullill Test.exe	V 0.0
Earphone & Microphone		
CF Card		

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1.5 The Support Units

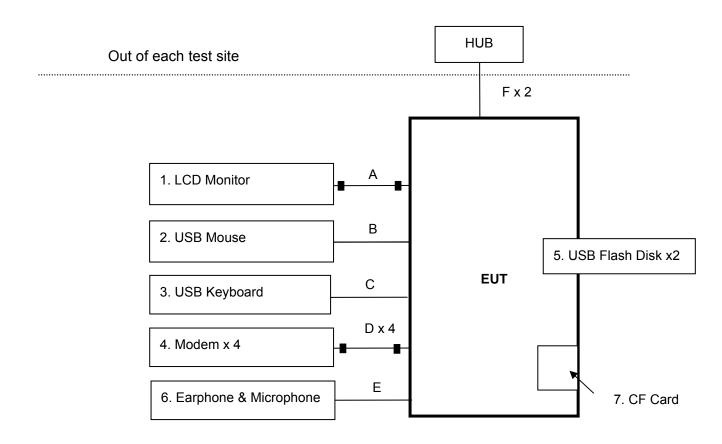
No.	Unit	Model No./ Serial No.	FCC ID	Trade Name	Power Cord	Supported by lab.
		2408WFP ^(Note 1) /				
		CN-0NN792-74261-	DoC	DELL	1.8m	✓
1	Monitor	849-154S				
,	in or me.	U2410 ^(Note2) /				
		CN-0J257M-72872- 083-069L	DoC	DELL	1.8m	✓
2	USB	MO56UC/	DoC	DELL	N/A	✓
	Mouse	516034297	DOC	DLLL	IN/A	•
	USB Keyboard	SK-8115/			N/A	✓
3			DoC	DELL		
		55G-0AGX				
	Modem	DM-1414/0311055092	IFAXDH1414	ACEEX	1.9m	✓
4		DM-1414/0509019802	IFAXDH1414	ACEEX	1.9m	✓
		DM-1414/0509019805	IFAXDH1414	ACEEX	1.9m	✓
		DM-1414/0509019801	IFAXDH1414	ACEEX	1.9m	✓
5	USB Flash	U172/100-029	DoC	PQI	N/A	✓
٥	Disk	U172/100-038	DoC	PQI	N/A	✓
6	Earphone &	ET-E220/2009-005 ^(Note 1)	N/A	ERGOTECH Technology	N/A	✓
	Microphone	AM-110/20090715-4 ^(Note 2)	DoC	andymay	N/A	✓
7	CF Card (8GB)	N/A	N/A	INNODISK	N/A	

Note 1: Used for Conducted Emission Test.

Note 2: Used for Radiated Emission Test.

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1.6 Layout of the Setup



Connecting Cables:

No.	Cable	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
Α	VGA Cable	1.7m	✓	✓		✓	2Cores
В	USB Mouse Cable	1.8m	✓			✓	
С	USB Keyboard Cable	1.8m	✓			✓	
D	Modem Cable	1.8m	✓	✓		✓	2Cores
	Earphone & Microphone Cable	1.8m	✓			✓	
F	LAN Cable	>3m				√	

1.7 Test Capability

Test Facility

The test facility used for evaluating the conformance of the EUT with each standard in the present report meets what required in CISPR16-1-4, CISPR16-2-3 and ANSI C63.4: 2003.

Test Room	Type of Test Room	Descriptions
TR1	10m semi-anechoic chamber (23m \times 14m \times 9m)	Complying with the NSA requirements in documents CISPR 22 and
TR11	3m semi-anechoic chamber	ANSI C63.4: 2003. for the radiated
IKII	$(9m \times 6m \times 6m)$	emission measurement.
TR5	Shielding Room	For the conducted emission
IKS	$(8m \times 5m \times 4m)$	measurement.

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Test Laboratory Competence Information

Central Research Technology Co. has been accredited / filed / authorized by the agencies listed in the following table.

Certificate	Nation	Agency	Code	Mark
	USA	NVLAP	200575-0	ISO/IEC 17025
	R.O.C. (Taiwan)	TAF	0905	ISO/IEC 17025
Accreditation Certificate	R.O.C. (Taiwan)	BSMI	SL2-IN-E-0033, SL2-IS-E-0033, SL2-R1/R2-E-0033, SL2-A1-E-0033 SL2-L1-E-0033	ISO/IEC 17025
	USA	FCC	474046,TW1053	Test facility list & NSA Data
Site Filing Document	Canada	IC	4699A-1,-3	Test facility list & NSA Data
	Japan	VCCI	R-1527,C-1609,T-1441,G-10	Test facility list & NSA Data
Authorization	Germany	TUV	10021687	ISO/IEC 17025
Certificate	Norway	Nemko	ELA 212	ISO/IEC 17025

The copy of each certificate can be downloaded from our web site: www.crc-lab.com

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2. Conducted Emission Measurement

Test Result : PASS

2.1 Limits for Emission Measurement

☑ Limits for conducted disturbances at the power mains

Frequency	Class A Equipment		Class B Equipment	
(MHz)	Quasi-peak	Average	Quasi-peak	Average
(1011 12)	(dBµV)	(dBµV)	(dBµV)	(dBµV)
0.15 to 0.5	79	66	66 – 56	56 – 46
0.5 to 5	73	60	56	46
5 to 30	73	60	60	50

Note 1- The lower limit shall apply at the transition frequency.

Note 2- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz for Class B equipment.

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Test Instruments 2.2

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Manufacturer	Serial No.	Calibration Date	Due Date	
Toot Doggiver	R&S	ESCS 30/	lon 14 2011	lan 14 2012	
Test Receiver	Κασ	836858/021	Jan. 14, 2011	Jan. 14, 2012	
LISN	R&S	ESH2-Z5/	June 2, 2011	June 2, 2012	
LISIN	κασ	836613/001	June 2, 2011	Julie 2, 2012	
2 nd LISN	R&S	ENV4200/	Jan. 14, 2011	lan 14 2012	
Z LISIN	κασ	833209/010	Jan. 14, 2011	Jan. 14, 2012	
50Ω terminator	N/A	N/A/	Aug. 20, 2011	Aug. 20, 2012	
5017 terminator	IN/A	001			
RF Switch	N/A	RSU28/	Aug. 20, 2011	Feb. 20, 2012	
KF SWILCH	IN/A	338965/002			
RF Cable	N/A	N/A/	Aug 20 2011	Fab 20 2012	
KF Cable	IN/A	C0052 ~ 56	Aug. 20, 2011	Feb. 20, 2012	
Test Software	Audix	e3/	NOD	NOD	
Test Software	Audix	Ver. 5.2004-2-19k	NCR	NCR	
TR5	ETS	TR5/	NCD	NCR	
shielded room	LINDGREN	15353-F	NCR	NCR	

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.

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Measurement Uncertainty

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Equipment	Model Number	Uncertainty Value
LISN	ESH2-Z5	3.1dB
	ENV 4200	2.8dB

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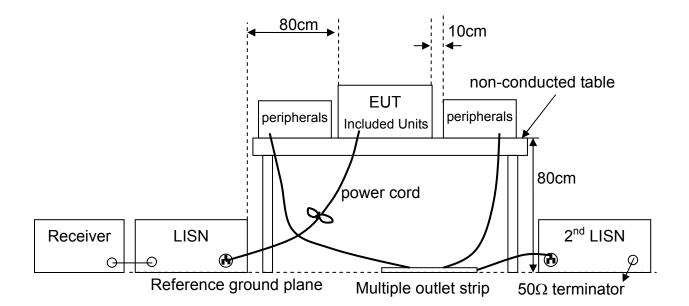
2.3 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane and 0.4 meters from the conducting wall of the shielded room. Also if the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 12 millimeters above the reference ground plane.
- c. Connect the EUT's power source to the appropriate power mains through the LISN.
- d. All the other peripherals are connected to the 2nd LISN, if any.
- e. The LISN was placed 0.8 meters from the EUT and at least 0.8 meters from other units and other metal planes.
- f. Measure the conducted emissions on each power line (Neutral Line and Line 1 Hot side) of the EUT's power source by using the test receiver connected to the coupling RF output port of LISN.
- g. Rapidly scan the signal from 150kHz to 30MHz by using the receiver through the Maximum-Peak detector to determine those frequencies associated with higher emission levels for each measured line.
- h. Then measure the maximum level of conducted disturbance for each frequency found from step g. by using the receiver through the Quasi-Peak and Average detectors per CISPR 16-1.
- i. Record the level for each frequency and compare with the required limit.

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2.4 Test Configurations



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Photographs of the Test Configurations 2.5





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2.6 Test Results

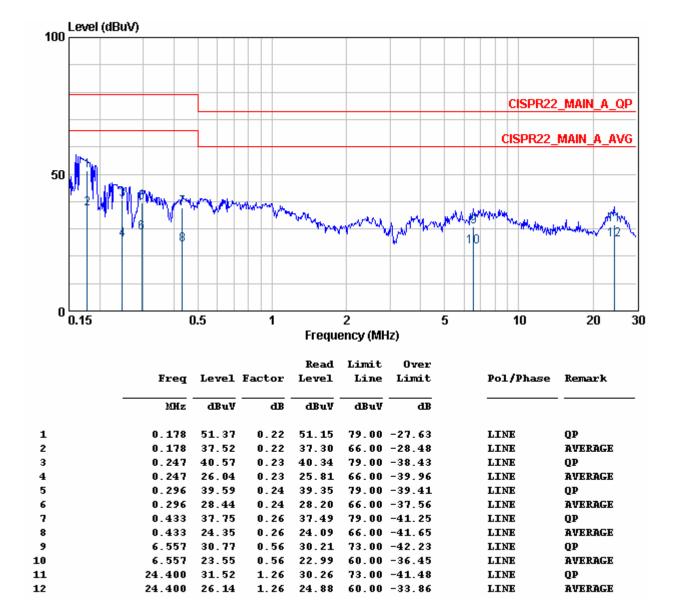
Test Mode: As description of section 1.2

Test Voltage: 120V/60Hz to the power adapter

Tester: Mathew **Temperature**: 24°C

Humidity: 53%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : Line



Note:

- Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN.
- Q.P. is abbreviation of quasi-peak.

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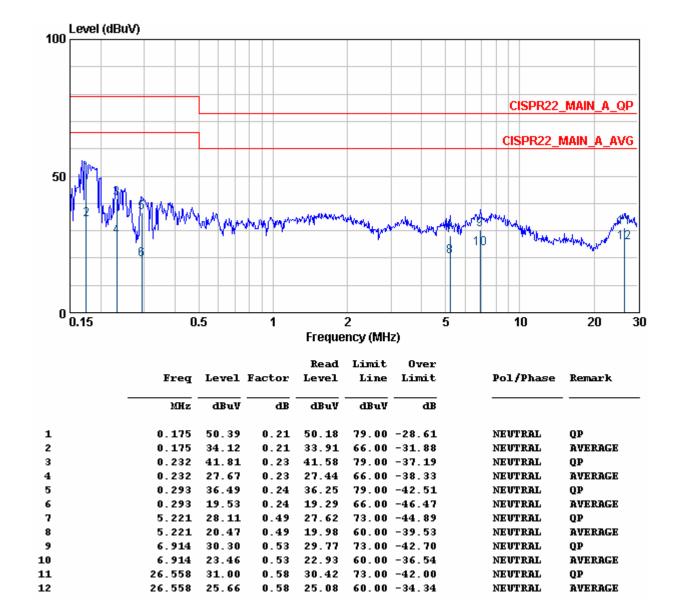
Test Mode: As description of section 1.2

Test Voltage: 120V/60Hz to the power adapter

Tester: Mathew **Temperature**: 24°C

Humidity: 53%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : Neutral



Note:

- Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.

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3. Radiated Emission Measurement

Test Result : PASS

3.1 Limits for Emission Measurement

☑ Limits for radiated disturbances below 1000MHz

Frequency	Class A Equipment (10m distance)	Class B Equipment (3m distance)
(MHz)	Quasi-peak	Quasi-peak
	(dBµV/m)	(dBµV/m)
30 to 88	39.1	40
88 to 216	43.5	43.5
216 to 960	46.4	46
960 to 1000	49.5	54

Note 1- The lower limit shall apply at the transition frequency.

Note 2- Additional provisions may be required for cases where interference occurs.

Note 3- According to 15.109(g), as an alternative to the radiated emission limits shown above, digital devices may be shown to comply with the standards (CISPR), Pub. 22 shown as below.

- P		
30 to 230	40	30
230 to 1000	47	37

☐ Limits for radiated disturbances in the frequency range 1000MHz ~ 2000MHz at a measuring distance of 10m

Frequency	Class A Ed	quipment	Class B Equipment		
(GHz)	Peak	Average	Peak	Average	
(0112)	(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)	
1 to 2	69.5	49.5	63.5	43.5	

☑ Limits for radiated disturbances above 1000MHz at a measuring distance of 3m

Frequency	Class A Ed	quipment	Class B Equipment	
(GHz)	Peak	Average	Peak	Average
(0112)	(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)
1 to 40	80	60	74	54

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3.2 Test Instruments

☑ For Measurement at the distance of 10m

Test Site and	Manufacturer	Model No./	Last	Calibration
Equipment	Manufacturer	Serial No.	Calibration Date	Due Date
EMI Test Receiver	R&S	ESCS 30/ 836858/020	Sept. 8, 2011	Sept. 8, 2012
Broadband Antenna	R&S	HL-562/ 360543/007	March 29, 2011	March 29, 2012
Broadband Antenna	R&S	HL-562/ 830547/010	April 26, 2011	April 26, 2012
Pre-Amplifier	Mini Circuit	ZKL-2/ 001	July 18, 2011	Jan. 18, 2012
Pre-Amplifier	Mini Circuit	ZKL-2/ 002	July 18, 2011	Jan. 18, 2012
Spectrum	R&S	FSP7/ 100108	June 10, 2011	June 10, 2012
Spectrum	R&S	FSP40/ 100031	July 4, 2011	July 4, 2012
RF Cable	JYEBAO	0214/ C0049	July 18, 2011	Jan. 18, 2012
RF Cable	JYEBAO	0214/ C0050	July 18, 2011	Jan. 18, 2012
Test Software	Audix	e3/ Ver. 4.3.714.e	NCR	NCR
TR1 Semi - anechoic Chamber	ETS. LINDGREN	TR1/ 17627-B	April 23, 2011	April 23, 2012

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- The calibration date of the semi-anechoic chamber listed above is the date of NSA measurement.

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☑ For Measurement at the distance of 3m

Test Site and	Manufacturor	Model No./		Last	Calibration	
Equipment	Wallulacture		Serial No.	Calibration Date	Due Date	
EMI Test	R&S		ESCI/	May 25, 2011	May 25, 2012	
Receiver	1100		100019	Way 20, 2011		
Bi-Log Antenna	EMCO		3142C/	May 19, 2011	May 19, 2012	
2. 2097			52088			
Horn Antenna	EMCO		3117/	March 1, 2011	March 1, 2012	
			00082847	, -	, ,	
Bore-sight	Sunol		TLT2/	NCR	NCR	
Antenna Mast			051110-5			
	KMIC		KMA010180A01/	Oct. 12, 2011	Oct. 12, 2012	
			99056			
	Mini Circuit		ZKL-2/	A C 2011	Feb. 6, 2012	
			004	Aug. 6, 2011		
Pre-Amplifier						
	MITEQ		JS4-00101800-	Dec. 21, 2011	Dec. 21, 2012	
		28-10P/1498979		200. 21, 2011	21, 2012	
			JS4-00101800-		Dec. 14, 2012	
	MITEQ	28-5A/742309		Dec. 14, 2011		
Spectrum			E4407B/			
Analyzer	Agilent		MY45106795	May 2, 2011	May 2, 2012	
RF Cable	N/A		N/A/	Aug. 6, 2011	Feb. 6, 2012	
THE GABIE	14/7 (C0080		Aug. 0, 2011	1 CD. 0, 2012	
RF Cable	N/A	N/A/ C0081		Oct. 17, 2011	April 17, 2012	
			e3/			
Test Software	Audix	Ver. 4.3.714.e		NCR	NCR	
TR11		TR11/ 906-A				
Semi - anechoic	ETS.			April 17, 2011	April 17, 2012	
Chamber	LINDGREN				,	

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the semi-anechoic chamber listed above is the date of NSA measurement.

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Measurement Uncertainty

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Test Site	Polarization -	Frequency Range		
(Measuring distance)	1 Glarization	30MHz ~200MHz	200MHz ~1000MHz	
TR1(10m)	Horizontal	3.5dB	3.9dB	
Tivi(Tolli)	Vertical	3.5dB	3.9dB	
TR11(3m)	Horizontal	3.5dB	3.9dB	
Tivi (om)	Vertical	3.8dB	3.9dB	

Test Site	Polarization -	Frequency Range		
(Measuring distance)	1 Glarization	1GHz ~18GHz	18GHz~26GHz	
TR11(3m)	Horizontal	3.5dB	4.4dB	
(6111)	Vertical	3.6dB	4.5dB	

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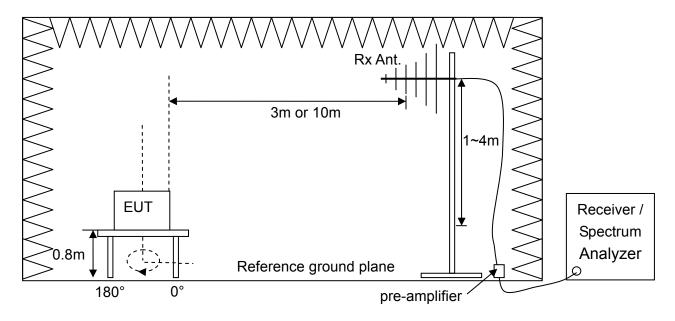
Test Procedures 3.3

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane in the semi-anechoic chamber. If the EUT is floor-standing equipment, it was placed on a nonconducted support with a height of 12 millimeters above the reference ground plane in the semi-anechoic chamber.
- c. For the measurement of frequency below 1000MHz, the EUT was set 10m away from the interference receiving antenna for the limit of Class A equipment or CISPR 22. For Class B equipment and the measurement of frequency above 1000MHz, the EUT was set 3m away from the interference receiving antenna.
- d. Rapidly sweep the signal in the test frequency range by using the spectrum through the Maximum-peak detector.
- e. Rotate the EUT from 0° to 360° and position the receiving antenna at heights from 1 to 4 meters above the reference ground plane continuously to determine at least six frequencies associated with higher emission levels and record them.
- f. For measurement of frequency above 1000MHz, the beamwidth of receiving horn antenna should keep covering EUT when the receiving horn antenna height varied.
- g. Then measure each frequency found from step e. by using the spectrum with rotating the EUT and positioning the receiving antenna height to determine the maximum level.
- h. Finely tune the antenna and turntable around the recorded position of each frequency found from step f.
- i. For measurement of frequency below 1000MHz, set the receiver detector to be Quasi-Peak per CISPR 16-1 to find out the maximum level occurred.
- j. For measurement of frequency above 1000MHz, set the spectrum detector to be Peak or Average to find out the maximum level occurred, if any.
- k. Record frequency, azimuth angle of the turntable, height, and polarization of the receiving antenna and compare the maximum level with the required limit.
- I. Change the receiving antenna to another polarization to measure radiated emission by following step d. to k. again.
- m. If the peak emission level measured from step e. is 4dB lower than the limit specified, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. value will be measured and presented.

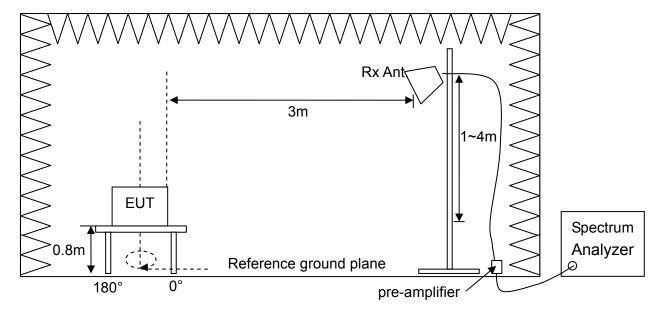
11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C. TEL.: 886-2-25984542

3.4 Test Configurations

Radiated Emission Measurement below 2000MHz



Radiated Emission Measurement above 1000MHz (if any)



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3.5 Photographs of the Test Configurations





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3.6 Test Results

Radiated Emission Measurement below 1000MHz

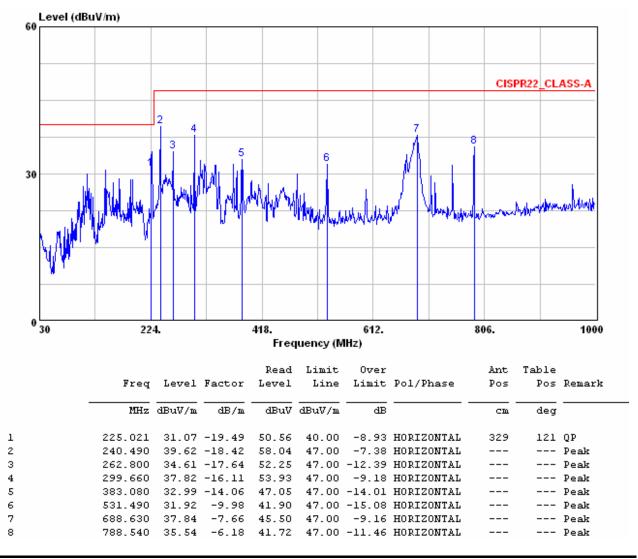
Test Mode : As description of section 1.2

Test Voltage: 120V/60Hz to the power adapter

Tester: Meng **Temperature**: 22°C

Humidity: 56%RH **Frequency Range**: 30MHz~1GHz

IF Bandwidth: 120kHz Polarization: Horizontal



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

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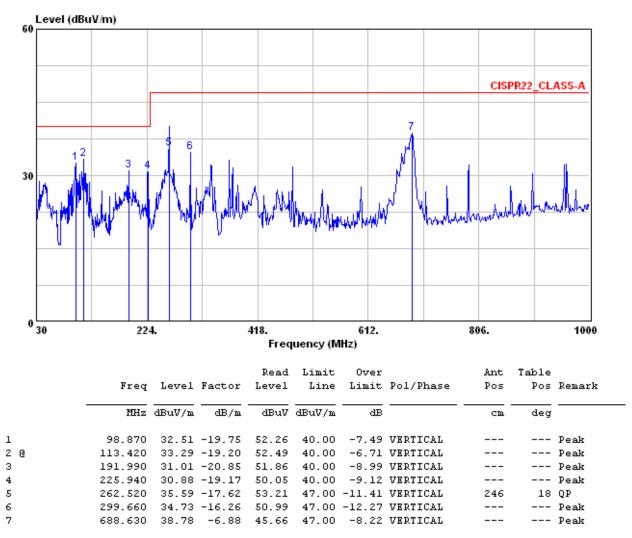
Test Mode: As description of section 1.2

Test Voltage: 120V/60Hz to the power adapter

Tester: Meng **Temperature**: 22°C

Humidity: 56%RH Frequency Range: 30MHz~1GHz

IF Bandwidth: 120kHz Polarization: Vertical



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

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Radiated Emission Measurement above 1000MHz

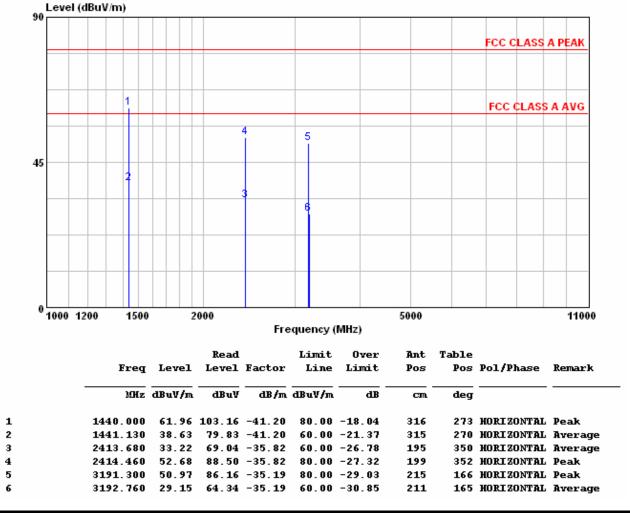
Test Mode: As description of section 1.2

Test Voltage: 120V/60Hz to the power adapter

Tester: Meng **Temperature**: 22°C

Humidity: 56%RH Frequency Range: 1GHz ~11GHz

IF Bandwidth: 1MHz Polarization: Horizontal



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

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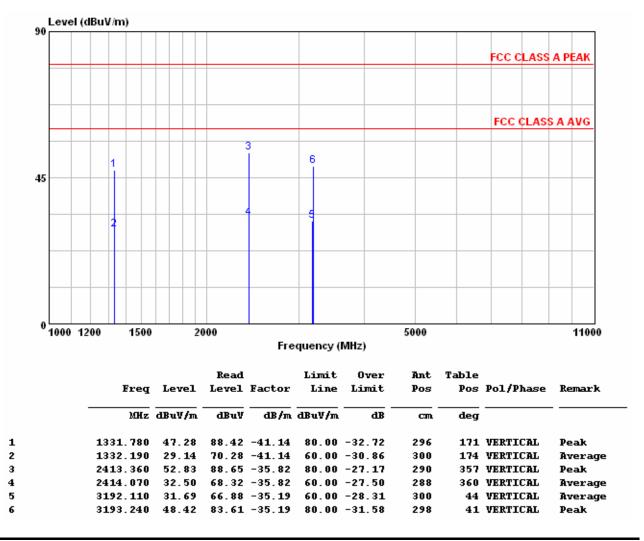
Test Mode: As description of section 1.2

Test Voltage: 120V/60Hz to the power adapter

Tester: Meng **Temperature**: 22°C

Humidity: 56%RH Frequency Range: 1GHz ~11GHz

IF Bandwidth: 1MHz Polarization: Vertical



Note:

- Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

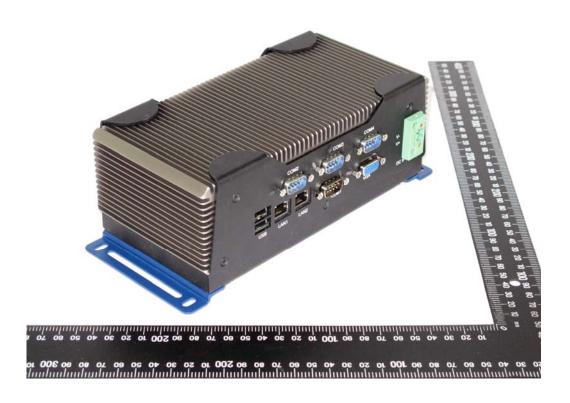
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Attachment 1 Photographs of EUT

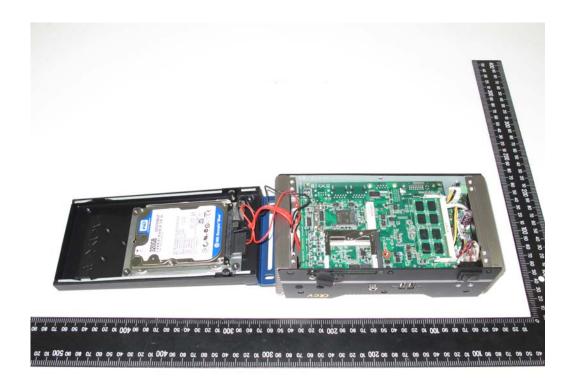
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Power Adapter

FSP FSP060-DBAB1











CF Card



Attachment 2 Modifications of EUT

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Statement of the EUT Modifications

According to the	ruies	s of ANSI C63.4-2003 clause 10.1.13, the following equipment
(EUT):		
Product	:	Fanless embedded controller
Model No.	:	xxxxxAEC-6613-xxxxxxxx (Where x is 0-9 , A-Z , -or blank)
		for marketing purpose
Manufacturer	:	AAEON Technology Inc.
Address	:	5F, NO.135, Lane 235, Pao Chiao Rd. Hsin-Tien Dist, New Taipei City, Taiwan, R.O.C
□ should be <u>wit</u>	<u>hout</u>	any modifications made
\square should be $\underline{\text{wit}}$	<u>h</u> sor	me modifications made
We , AA	. EON e wil	e described in next page of this report. I Technology Inc. hereby ensure that the product specified I have all of the modifications incorporated in the product when aced on the market.
The following im	porte	r or manufacturer is responsible for this statement:
Company Name	:	
Company Addres	ss :	
Telephone	:	E-mail :
Legal Signature	of the	e responsible personal:
Title /	Nan	ne (full name) Date

CENTRAL RESEARCH TECHNOLOGY CO. 11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.

The details of the modifications:

Item	Solution Component	Specifications	Manufacturer	Quantity	Reasons
1					
2					
3					
4					
5					
6					
7					
8					
9					
10					
11					
12					
13					
14					
15					

If needed, some modification items are shown in the photographs in the following.